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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	300MHz
Co-Processors/DSP	-
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	255-BBGA, FCBGA
Supplier Device Package	255-FCPBGA (21x21)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc745bpx300le

2 Features

This section summarizes features of the MPC755 implementation of the PowerPC architecture. Major features of the MPC755 are as follows:

- Branch processing unit
  - Four instructions fetched per clock
  - One branch processed per cycle (plus resolving two speculations)
  - Up to one speculative stream in execution, one additional speculative stream in fetch
  - 512-entry branch history table (BHT) for dynamic prediction
  - 64-entry, four-way set-associative branch target instruction cache (BTIC) for eliminating branch delay slots
- Dispatch unit
  - Full hardware detection of dependencies (resolved in the execution units)
  - Dispatch two instructions to six independent units (system, branch, load/store, fixed-point unit 1, fixed-point unit 2, floating-point)
  - Serialization control (predispatch, postdispatch, execution serialization)
- Decode
  - Register file access
  - Forwarding control
  - Partial instruction decode
- Completion
  - Six-entry completion buffer
  - Instruction tracking and peak completion of two instructions per cycle
  - Completion of instructions in program order while supporting out-of-order instruction execution, completion serialization, and all instruction flow changes
- Fixed point units (FXUs) that share 32 GPRs for integer operands
  - Fixed Point Unit 1 (FXU1)—multiply, divide, shift, rotate, arithmetic, logical
  - Fixed Point Unit 2 (FXU2)—shift, rotate, arithmetic, logical
  - Single-cycle arithmetic, shifts, rotates, logical
  - Multiply and divide support (multi-cycle)
  - Early out multiply
- Floating-point unit and a 32-entry FPR file
  - Support for IEEE standard 754 single- and double-precision floating-point arithmetic
  - Hardware support for divide
  - Hardware support for denormalized numbers
  - Single-entry reservation station
  - Supports non-IEEE mode for time-critical operations
  - Three-cycle latency, one-cycle throughput, single-precision multiply-add

Table 4. Package Thermal Characteristics [6]

Characteristic	Symbol	Value			Unit	Notes
		MPC755 CBGA	MPC755 PBGA	MPC745 PBGA		
Junction-to-ambient thermal resistance, natural convection	$R_{\theta JA}$	24	31	34	°C/W	1, 2
Junction-to-ambient thermal resistance, natural convection, four-layer (2s2p) board	$R_{\theta JMA}$	17	25	26	°C/W	1, 3
Junction-to-ambient thermal resistance, 200 ft/min airflow, single-layer (1s) board	$R_{\theta JMA}$	18	25	27	°C/W	1, 3
Junction-to-ambient thermal resistance, 200 ft/min airflow, four-layer (2s2p) board	$R_{\theta JMA}$	14	21	22	°C/W	1, 3
Junction-to-board thermal resistance	$R_{\theta JB}$	8	17	17	°C/W	4
Junction-to-case thermal resistance	$R_{\theta JC}$	<0.1	<0.1	<0.1	°C/W	5

Notes:

1. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. The actual value of $R_{\theta JC}$ for the part is less than 0.1°C/W.
6. Refer to Section 8.8, "Thermal Management Information," for more details about thermal management.

The MPC755 incorporates a thermal management assist unit (TAU) composed of a thermal sensor, digital-to-analog converter, comparator, control logic, and dedicated special-purpose registers (SPRs). See the *MPC750 RISC Microprocessor Family User's Manual* for more information on the use of this feature. Specifications for the thermal sensor portion of the TAU are found in Table 5.

Table 5. Thermal Sensor Specifications

At recommended operating conditions (see Table 3)

Characteristic	Min	Max	Unit	Notes
Temperature range	0	127	°C	1
Comparator settling time	20	—	µs	2, 3
Resolution	4	—	°C	3
Accuracy	–12	+12	°C	3

Notes:

1. The temperature is the junction temperature of the die. The thermal assist unit's raw output does not indicate an absolute temperature, but must be interpreted by software to derive the absolute junction temperature. For information about the use and calibration of the TAU, see Freescale Application Note AN1800/D, *Programming the Thermal Assist Unit in the MPC750 Microprocessor.*
2. The comparator settling time value must be converted into the number of CPU clocks that need to be written into the THRM3 SPR.
3. Guaranteed by design and characterization.

Table 6 provides the DC electrical characteristics for the MPC755.

Table 6. DC Electrical Specifications

At recommended operating conditions (see Table 3)

Characteristic	Nominal Bus Voltage [1]	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs except SYSCLK)	2.5	V_{IH}	1.6	(L2)OV_{DD} + 0.3	V	2, 3
	3.3	V_{IH}	2.0	(L2)OV_{DD} + 0.3	V	2, 3
Input low voltage (all inputs except SYSCLK)	2.5	V_{IL}	–0.3	0.6	V	2
	3.3	V_{IL}	–0.3	0.8	V	
SYSCLK input high voltage	2.5	KV_{IH}	1.8	OV_{DD} + 0.3	V	
	3.3	KV_{IH}	2.4	OV_{DD} + 0.3	V	
SYSCLK input low voltage	2.5	KV_{IL}	–0.3	0.4	V	
	3.3	KV_{IL}	–0.3	0.4	V	
Input leakage current, V_{in} = L2OV_{DD}/OV_{DD}		I_{in}	—	10	µA	2, 3
High-Z (off-state) leakage current, V_{in} = L2OV_{DD}/OV_{DD}		I_{TSI}	—	10	µA	2, 3, 5
Output high voltage, I_{OH} = –6 mA	2.5	V_{OH}	1.7	—	V	
	3.3	V_{OH}	2.4	—	V	
Output low voltage, I_{OL} = 6 mA	2.5	V_{OL}	—	0.45	V	
	3.3	V_{OL}	—	0.4	V	

4.2 AC Electrical Characteristics

This section provides the AC electrical characteristics for the MPC755. After fabrication, functional parts are sorted by maximum processor core frequency as shown in Section 4.2.1, "Clock AC Specifications," and tested for conformance to the AC specifications for that frequency. The processor core frequency is determined by the bus (SYSCLK) frequency and the settings of the PLL_CFG[0:3] signals. Parts are sold by maximum processor core frequency; see Section 10, "Ordering Information."

4.2.1 Clock AC Specifications

Table 8 provides the clock AC timing specifications as defined in Figure 3.

Table 8. Clock AC Timing Specifications

At recommended operating conditions (see Table 3)

Characteristic	Symbol	Maximum Processor Core Frequency						Unit	Notes
		300 MHz		350 MHz		400 MHz			
		Min	Max	Min	Max	Min	Max		
Processor frequency	f_{core}	200	300	200	350	200	400	MHz	1
VCO frequency	f_{VCO}	400	600	400	700	400	800	MHz	1
SYSCLK frequency	f_{SYSCLK}	25	100	25	100	25	100	MHz	1
SYSCLK cycle time	t_{SYSCLK}	10	40	10	40	10	40	ns	
SYSCLK rise and fall time	t_{KR}, t_{KF}	—	2.0	—	2.0	—	2.0	ns	2
	t_{KR}, t_{KF}	—	1.4	—	1.4	—	1.4	ns	2
SYSCLK duty cycle measured at $OV_{DD}/2$	t_{KHKL}/t_{SYSCLK}	40	60	40	60	40	60	%	3
SYSCLK jitter		—	±150	—	±150	—	±150	ps	3, 4
Internal PLL relock time		—	100	—	100	—	100	μs	3, 5

Notes:

1. **Caution:** The SYSCLK frequency and PLL_CFG[0:3] settings must be chosen such that the resulting SYSCLK (bus) frequency, CPU (core) frequency, and PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies. Refer to the PLL_CFG[0:3] signal description in Section 8.1, "PLL Configuration," for valid PLL_CFG[0:3] settings.
2. Rise and fall times measurements are now specified in terms of slew rates, rather than time to account for selectable I/O bus interface levels. The minimum slew rate of 1 V/ns is equivalent to a 2 ns maximum rise/fall time measured at 0.4 and 2.4 V (OV_{DD} = 3.3 V) or a rise/fall time of 1 ns measured at 0.4 and 1.8 V (OV_{DD} = 2.5 V).
3. Timing is guaranteed by design and characterization.
4. This represents total input jitter—short term and long term combined—and is guaranteed by design.
5. Relock timing is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for PLL lock after a stable V_{DD} and SYSCLK are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep mode. Also note that $\overline{\text{HRESET}}$ must be held asserted for a minimum of 255 bus clocks after the PLL-relock time during the power-on reset sequence.

SRAM. Note that revisions of the MPC755 prior to Rev. 2.8 (Rev. E) were limited in performance, and were typically limited to 175 MHz with similarly-rated SRAM. For more information, see Section 10.2, “Part Numbers Not Fully Addressed by This Document.”

Freescale is similarly limited by system constraints and cannot perform tests of the L2 interface on a socketed part on a functional tester at the maximum frequencies of Table 11. Therefore, functional operation and AC timing information are tested at core-to-L2 divisors of 2 or greater. Functionality of core-to-L2 divisors of 1 or 1.5 is verified at less than maximum rated frequencies.

L2 input and output signals are latched or enabled, respectively, by the internal L2CLK (which is SYSCLK multiplied up to the core frequency and divided down to the L2CLK frequency). In other words, the AC timings of Table 12 and Table 13 are entirely independent of L2SYNC_IN. In a closed loop system, where L2SYNC_IN is driven through the board trace by L2SYNC_OUT, L2SYNC_IN only controls the output phase of L2CLK_OUTA and L2CLK_OUTB which are used to latch or enable data at the SRAMs. However, since in a closed loop system L2SYNC_IN is held in phase alignment with the internal L2CLK, the signals of Table 12 and Table 13 are referenced to this signal rather than the not-externally-visible internal L2CLK. During manufacturing test, these times are actually measured relative to SYSCLK.

The L2SYNC_OUT signal is intended to be routed halfway out to the SRAMs and then returned to the L2SYNC_IN input of the MPC755 to synchronize L2CLK_OUT at the SRAM with the processor’s internal clock. L2CLK_OUT at the SRAM can be offset forward or backward in time by shortening or lengthening the routing of L2SYNC_OUT to L2SYNC_IN. See Freescale Application Note AN1794/D, *Backside L2 Timing Analysis for PCB Design Engineers*.

The L2CLK_OUTA and L2CLK_OUTB signals should not have more than two loads.

Table 11. L2CLK Output AC Timing Specification

At recommended operating conditions (see Table 3)

Parameter	Symbol	All Speed Grades		Unit	Notes
		Min	Max		
L2CLK frequency	f_{L2CLK}	80	450	MHz	1, 4
L2CLK cycle time	t_{L2CLK}	2.5	12.5	ns	
L2CLK duty cycle	t_{CHCL}/t_{L2CLK}	45	55	%	2, 7
Internal DLL-relock time		640	—	L2CLK	3, 7
DLL capture window		0	10	ns	5, 7
L2CLK_OUT output-to-output skew	t_{L2CSKW}	—	50	ps	6, 7
L2CLK_OUT output jitter		—	±150	ps	6, 7

Notes:

1. L2CLK outputs are L2CLK_OUTA, L2CLK_OUTB, L2CLK_OUT, and L2SYNC_OUT pins. The L2CLK frequency-to-core frequency settings must be chosen such that the resulting L2CLK frequency and core frequency do not exceed their respective maximum or minimum operating frequencies. The maximum L2LCK frequency will be system dependent. L2CLK_OUTA and L2CLK_OUTB must have equal loading.
2. The nominal duty cycle of the L2CLK is 50% measured at midpoint voltage.
3. The DLL-relock time is specified in terms of L2CLK periods. The number in the table must be multiplied by the period of L2CLK to compute the actual time duration in ns. Relock timing is guaranteed by design and characterization.
4. The L2CR[L2SL] bit should be set for L2CLK frequencies less than 110 MHz. This adds more delay to each tap of the DLL.
5. Allowable skew between L2SYNC_OUT and L2SYNC_IN.
6. This output jitter number represents the maximum delay of one tap forward or one tap back from the current DLL tap as the phase comparator seeks to minimize the phase difference between L2SYNC_IN and the internal L2CLK. This number must be comprehended in the L2 timing analysis. The input jitter on SYSCLK affects L2CLK_OUT and the L2 address/data/control signals equally and, therefore, is already comprehended in the AC timing and does not have to be considered in the L2 timing analysis.
7. Guaranteed by design.

Table 12. L2 Bus Interface AC Timing Specifications (continued)

At recommended operating conditions (see Table 3)

Parameter	Symbol	All Speed Grades		Unit	Notes
		Min	Max		
L2SYNC_IN to high impedance: All outputs when L2CR[14–15] = 00 All outputs when L2CR[14–15] = 01 All outputs when L2CR[14–15] = 10 All outputs when L2CR[14–15] = 11	t_{L2CHOZ}	 — — — —	 2.4 2.6 2.8 3.0	ns	3, 5

Notes:

1. Rise and fall times for the L2SYNC_IN input are measured from 20% to 80% of $L2OV_{DD}$.
2. All input specifications are measured from the midpoint of the signal in question to the midpoint voltage of the rising edge of the input L2SYNC_IN (see Figure 8). Input timings are measured at the pins.
3. All output specifications are measured from the midpoint voltage of the rising edge of L2SYNC_IN to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 10).
4. The outputs are valid for both single-ended and differential L2CLK modes. For pipelined registered synchronous BurstRAMs, L2CR[14–15] = 01 or 10 is recommended. For pipelined late write synchronous BurstRAMs, L2CR[14–15] = 11 is recommended.
5. Guaranteed by design and characterization.
6. Revisions prior to Rev. 2.8 (Rev. E) were limited in performance and did not conform to this specification. For more information, refer to Section 10.2, “Part Numbers Not Fully Addressed by This Document.”

Figure 8 shows the L2 bus input timing diagrams for the MPC755.

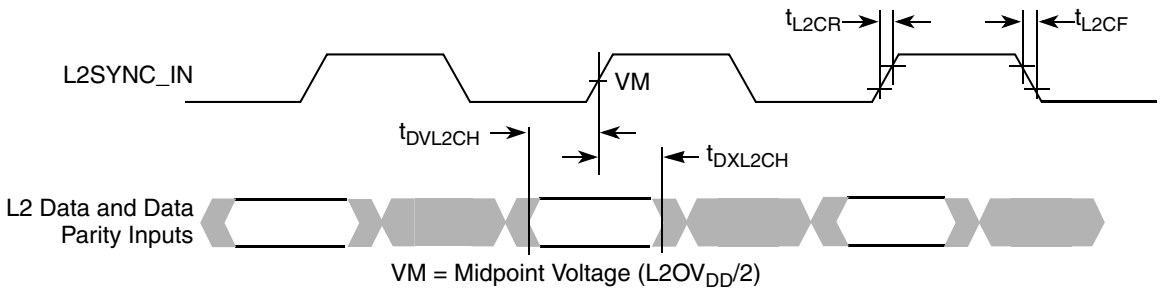


Figure 8. L2 Bus Input Timing Diagrams

4.2.5 IEEE 1149.1 AC Timing Specifications

Table 13 provides the IEEE 1149.1 (JTAG) AC timing specifications as defined in Figure 12 through Figure 15.

Table 13. JTAG AC Timing Specifications (Independent of SYSCLK) [1]

At recommended operating conditions (see Table 3)

Parameter		Symbol	Min	Max	Unit	Notes
TCK frequency of operation		f_{TCLK}	0	16	MHz	
TCK cycle time		t_{TCLK}	62.5	—	ns	
TCK clock pulse width measured at 1.4 V		t_{JHJL}	31	—	ns	
TCK rise and fall times		t_{JR}, t_{JF}	0	2	ns	
$\overline{\text{TRST}}$ assert time		t_{TRST}	25	—	ns	2
Input setup times:	Boundary-scan data TMS, TDI	t_{DVJH} t_{IVJH}	4 0	— —	ns	3
Input hold times:	Boundary-scan data TMS, TDI	t_{DXJH} t_{IXJH}	15 12	— —	ns	3
Valid times:	Boundary-scan data TDO	t_{JLDV} t_{JLOV}	— —	4 4	ns	4
Output hold times:	Boundary-scan data TDO	t_{JLDH} t_{JLOH}	25 12	— —	ns	4
TCK to output high impedance:	Boundary-scan data TDO	t_{JLDZ} t_{JLOZ}	3 3	19 9	ns	4, 5

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of TCLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 11). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. $\overline{\text{TRST}}$ is an asynchronous level sensitive signal which must be asserted for this minimum time to be recognized.
3. Non-JTAG signal input timing with respect to TCK.
4. Non-JTAG signal output timing with respect to TCK.
5. Guaranteed by design and characterization.

Figure 11 provides the AC test load for TDO and the boundary-scan outputs of the MPC755.

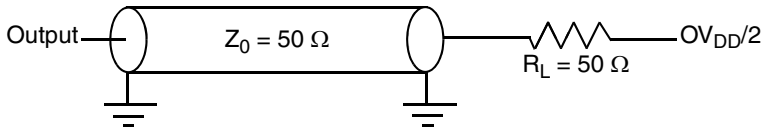


Figure 11. AC Test Load for the JTAG Interface

Figure 12 provides the JTAG clock input timing diagram.

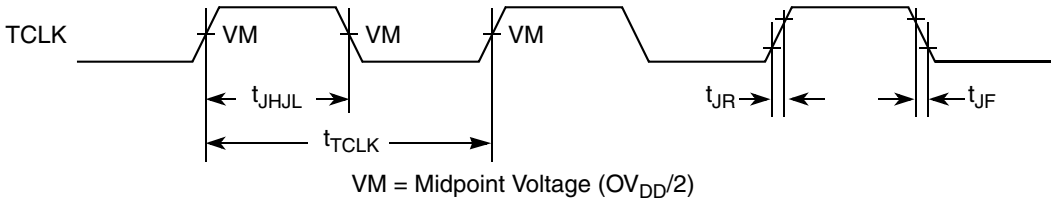


Figure 12. JTAG Clock Input Timing Diagram

Figure 13 provides the $\overline{\text{TRST}}$ timing diagram.

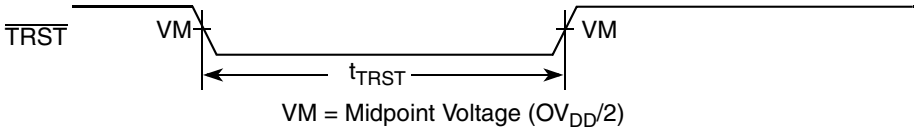


Figure 13. $\overline{\text{TRST}}$ Timing Diagram

Figure 14 provides the boundary-scan timing diagram.

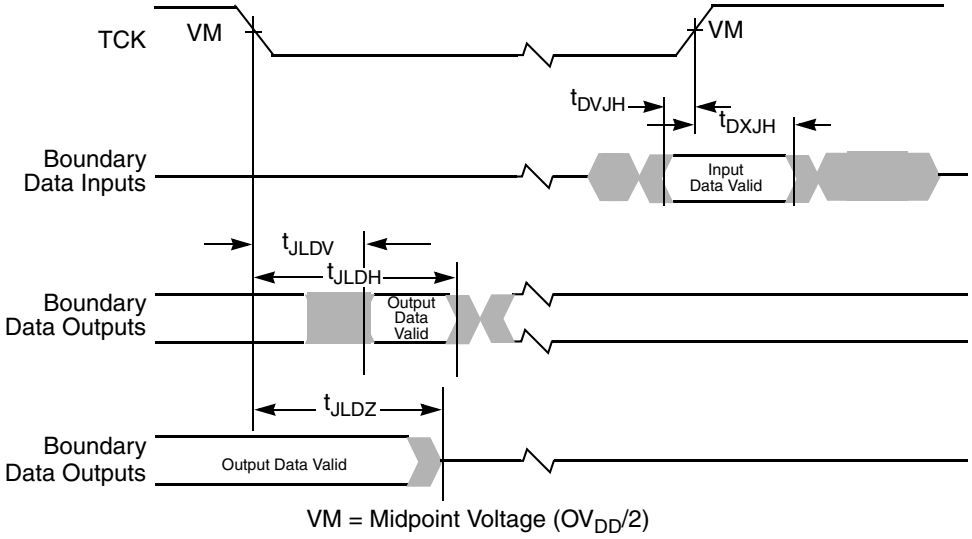


Figure 14. Boundary-Scan Timing Diagram

Figure 15 provides the test access port timing diagram.

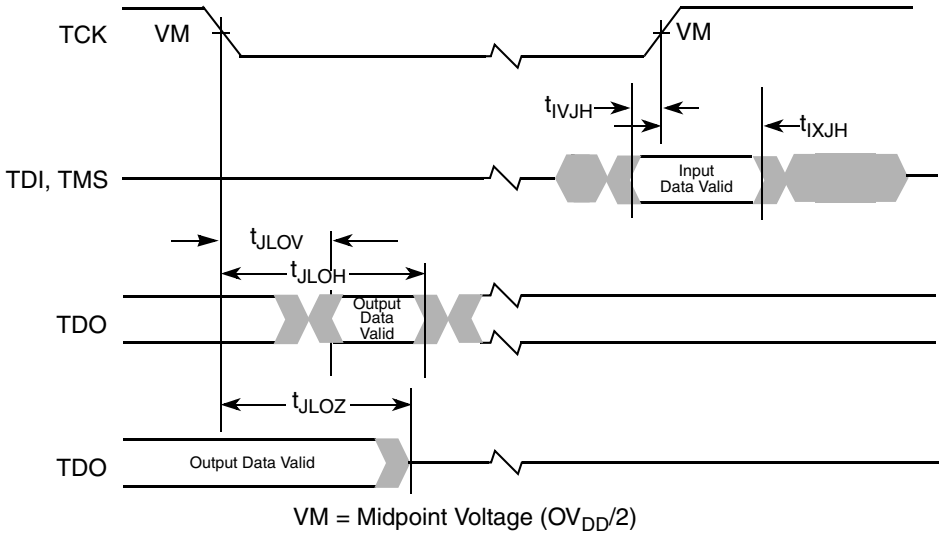


Figure 15. Test Access Port Timing Diagram

Table 14. Pinout Listing for the MPC745, 255 PBGA Package (continued)

Signal Name	Pin Number	Active	I/O	I/F Voltage [1]	Notes
VOLTDET	F3	High	Output	—	6

Notes:

1. OV_{DD} supplies power to the processor bus, JTAG, and all control signals; and V_{DD} supplies power to the processor core and the PLL (after filtering to become AV_{DD}). These columns serve as a reference for the nominal voltage supported on a given signal as selected by the BVSEL pin configuration of Table 2 and the voltage supplied. For actual recommended value of V_{in} or supply voltages, see Table 3.
2. These are test signals for factory use only and must be pulled up to OV_{DD} for normal machine operation.
3. This pin must be pulled up to OV_{DD} for proper operation of the processor interface. To allow for future I/O voltage changes, provide the option to connect BVSEL independently to either OV_{DD} or GND.
4. Uses 1 of 15 existing no connects in the MPC740, 255 BGA package.
5. Internal pull-up on die.
6. Internally tied to GND in the MPC745, 255 BGA package to indicate to the power supply that a low-voltage processor is present. This signal is not a power supply input.

   Caution: This differs from the MPC755, 360 BGA package.

Table 15 provides the pinout listing for the MPC755, 360 PBGA and CBGA packages.

Table 15. Pinout Listing for the MPC755, 360 BGA Package

Signal Name	Pin Number	Active	I/O	I/F Voltage [1]	Notes
A[0:31]	A13, D2, H11, C1, B13, F2, C13, E5, D13, G7, F12, G3, G6, H2, E2, L3, G5, L4, G4, J4, H7, E1, G2, F3, J7, M3, H3, J2, J6, K3, K2, L2	High	I/O	OV_{DD}	
$\overline{\text{AACK}}$	N3	Low	Input	OV_{DD}	
$\overline{\text{ABB}}$	L7	Low	I/O	OV_{DD}	
AP[0:3]	C4, C5, C6, C7	High	I/O	OV_{DD}	
$\overline{\text{ARTRY}}$	L6	Low	I/O	OV_{DD}	
AV_{DD}	A8	—	—	2.0 V	
$\overline{\text{BG}}$	H1	Low	Input	OV_{DD}	
$\overline{\text{BR}}$	E7	Low	Output	OV_{DD}	
BVSEL	W1	High	Input	OV_{DD}	3, 5, 6
$\overline{\text{CI}}$	C2	Low	Output	OV_{DD}	
$\overline{\text{CKSTP\_IN}}$	B8	Low	Input	OV_{DD}	
$\overline{\text{CKSTP\_OUT}}$	D7	Low	Output	OV_{DD}	
CLK_OUT	E3	—	Output	OV_{DD}	
$\overline{\text{DBB}}$	K5	Low	I/O	OV_{DD}	
$\overline{\text{DBDIS}}$	G1	Low	Input	OV_{DD}	
$\overline{\text{DBG}}$	K1	Low	Input	OV_{DD}	
$\overline{\text{DBWO}}$	D1	Low	Input	OV_{DD}	

Table 15. Pinout Listing for the MPC755, 360 BGA Package (continued)

Signal Name	Pin Number	Active	I/O	I/F Voltage [1]	Notes
DH[0:31]	W12, W11, V11, T9, W10, U9, U10, M11, M9, P8, W7, P9, W9, R10, W6, V7, V6, U8, V9, T7, U7, R7, U6, W5, U5, W4, P7, V5, V4, W3, U4, R5	High	I/O	OV_{DD}	
DL[0:31]	M6, P3, N4, N5, R3, M7, T2, N6, U2, N7, P11, V13, U12, P12, T13, W13, U13, V10, W8, T11, U11, V12, V8, T1, P1, V1, U1, N1, R2, V3, U3, W2	High	I/O	OV_{DD}	
DP[0:7]	L1, P2, M2, V2, M1, N2, T3, R1	High	I/O	OV_{DD}	
$\overline{\text{DRTRY}}$	H6	Low	Input	OV_{DD}	
$\overline{\text{GBL}}$	B1	Low	I/O	OV_{DD}	
GND	D10, D14, D16, D4, D6, E12, E8, F4, F6, F10, F14, F16, G9, G11, H5, H8, H10, H12, H15, J9, J11, K4, K6, K8, K10, K12, K14, K16, L9, L11, M5, M8, M10, M12, M15, N9, N11, P4, P6, P10, P14, P16, R8, R12, T4, T6, T10, T14, T16	—	—	GND	
$\overline{\text{HRESET}}$	B6	Low	Input	OV_{DD}	
$\overline{\text{INT}}$	C11	Low	Input	OV_{DD}	
L1_TSTCLK	F8	High	Input	—	2
L2ADDR[16:0]	G18, H19, J13, J14, H17, H18, J16, J17, J18, J19, K15, K17, K18, M19, L19, L18, L17	High	Output	$L2OV_{DD}$	
$L2AV_{DD}$	L13	—	—	2.0 V	
$\overline{\text{L2CE}}$	P17	Low	Output	$L2OV_{DD}$	
L2CLK_OUTA	N15	—	Output	$L2OV_{DD}$	
L2CLK_OUTB	L16	—	Output	$L2OV_{DD}$	
L2DATA[0:63]	U14, R13, W14, W15, V15, U15, W16, V16, W17, V17, U17, W18, V18, U18, V19, U19, T18, T17, R19, R18, R17, R15, P19, P18, P13, N14, N13, N19, N17, M17, M13, M18, H13, G19, G16, G15, G14, G13, F19, F18, F13, E19, E18, E17, E15, D19, D18, D17, C18, C17, B19, B18, B17, A18, A17, A16, B16, C16, A14, A15, C15, B14, C14, E13	High	I/O	$L2OV_{DD}$	
L2DP[0:7]	V14, U16, T19, N18, H14, F17, C19, B15	High	I/O	$L2OV_{DD}$	
$L2OV_{DD}$	D15, E14, E16, H16, J15, L15, M16, P15, R14, R16, T15, F15	—	—	$L2OV_{DD}$	
L2SYNC_IN	L14	—	Input	$L2OV_{DD}$	
L2SYNC_OUT	M14	—	Output	$L2OV_{DD}$	
L2_TSTCLK	F7	High	Input	—	2
L2VSEL	A19	High	Input	$L2OV_{DD}$	1, 5, 6, 7
$\overline{\text{L2WE}}$	N16	Low	Output	$L2OV_{DD}$	

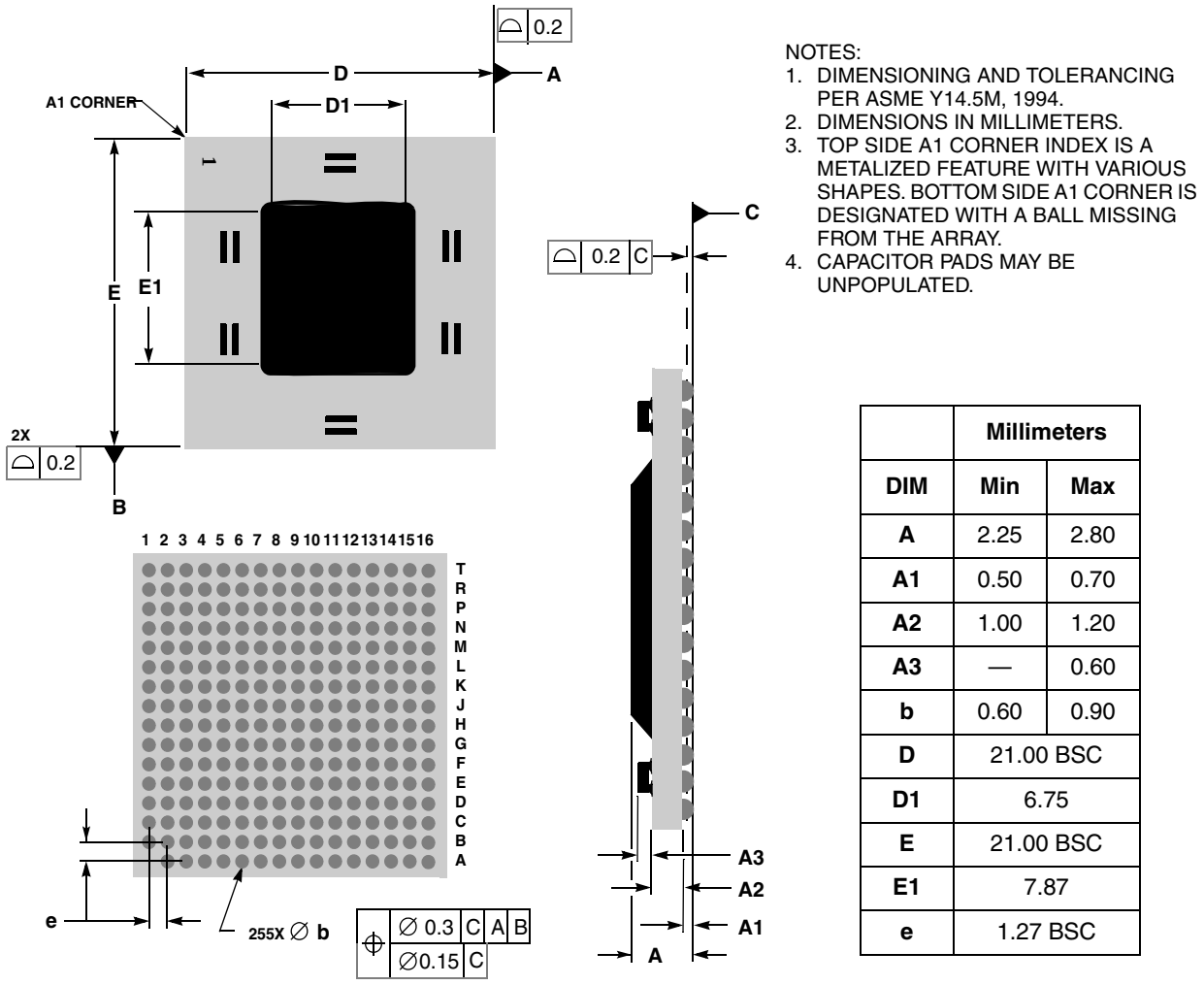
7.1 Package Parameters for the MPC745 PBGA

The package parameters are as provided in the following list. The package type is 21 × 21 mm, 255-lead plastic ball grid array (PBGA).

Package outline	21 × 21 mm
Interconnects	255 (16 × 16 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.25 mm
Maximum module height	2.80 mm
Ball diameter (typical)	0.75 mm (29.5 mil)

7.2 Mechanical Dimensions for the MPC745 PBGA

Figure 18 provides the mechanical dimensions and bottom surface nomenclature for the MPC745, 255 PBGA package.



	Millimeters	
DIM	Min	Max
A	2.25	2.80
A1	0.50	0.70
A2	1.00	1.20
A3	—	0.60
b	0.60	0.90
D	21.00 BSC	
D1	6.75	
E	21.00 BSC	
E1	7.87	
e	1.27 BSC	

Figure 18. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC745, 255 PBGA Package

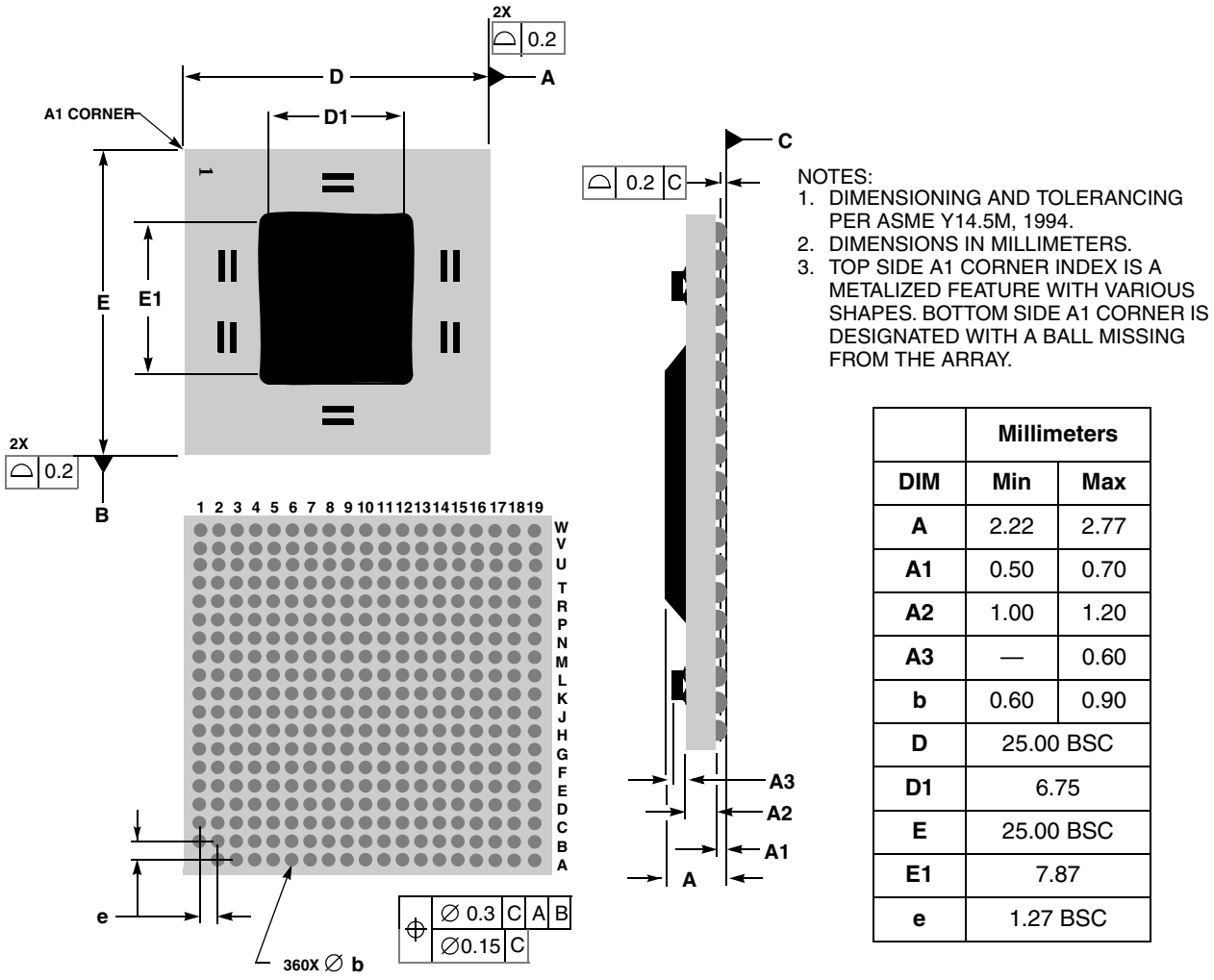
7.5 Package Parameters for the MPC755 PBGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360-lead plastic ball grid array (PBGA).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.22 mm
Maximum module height	2.77 mm
Ball diameter	0.75 mm (29.5 mil)

7.6 Mechanical Dimensions for the MPC755

Figure 20 provides the mechanical dimensions and bottom surface nomenclature for the MPC755, 360 PBGA package.



	Millimeters	
DIM	Min	Max
A	2.22	2.77
A1	0.50	0.70
A2	1.00	1.20
A3	—	0.60
b	0.60	0.90
D	25.00 BSC	
D1	6.75	
E	25.00 BSC	
E1	7.87	
e	1.27 BSC	

Figure 20. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC755, 360 PBGA Package

Figure 22 describes the driver impedance measurement circuit described above.

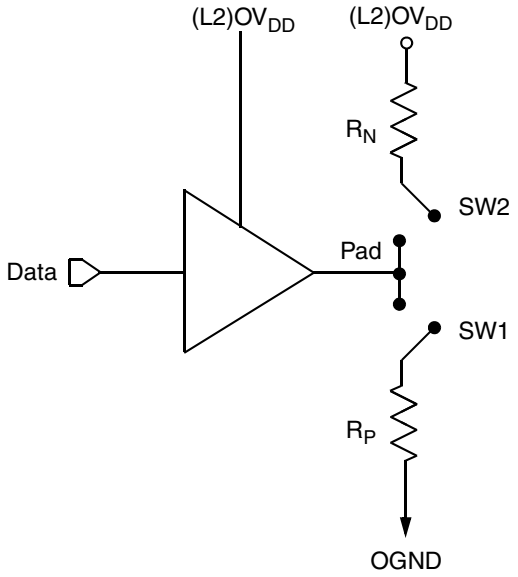


Figure 22. Driver Impedance Measurement Circuit

Alternately, the following is another method to determine the output impedance of the MPC755. A voltage source, V_{force}, is connected to the output of the MPC755 as shown in Figure 23. Data is held low, the voltage source is set to a value that is equal to (L2)OV_{DD}/2 and the current sourced by V_{force} is measured. The voltage drop across the pull-down device, which is equal to (L2)OV_{DD}/2, is divided by the measured current to determine the output impedance of the pull-down device, R_N. Similarly, the impedance of the pull-up device is determined by dividing the voltage drop of the pull-up, (L2)OV_{DD}/2, by the current sank by the pull-up when the data is high and V_{force} is equal to (L2)OV_{DD}/2. This method can be employed with either empirical data from a test setup or with data from simulation models, such as IBIS.

R_P and R_N are designed to be close to each other in value. Then $Z_0 = (R_P + R_N)/2$.

Figure 23 describes the alternate driver impedance measurement circuit.

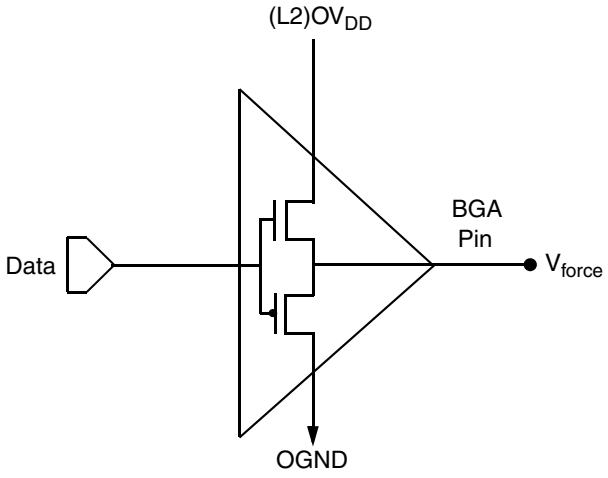


Figure 23. Alternate Driver Impedance Measurement Circuit

There is no standardized way to number the COP header shown in Figure 24; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 25 is common to all known emulators.

The $\overline{\text{QACK}}$ signal shown in Figure 24 is usually connected to the PCI bridge chip in a system and is an input to the MPC755 informing it that it can go into the quiescent state. Under normal operation this occurs during a low-power mode selection. In order for COP to work, the MPC755 must see this signal asserted (pulled down). While shown on the COP header, not all emulator products drive this signal. If the product does not, a pull-down resistor can be populated to assert this signal. Additionally, some emulator products implement open-drain type outputs and can only drive $\overline{\text{QACK}}$ asserted; for these tools, a pull-up resistor can be implemented to ensure this signal is deasserted when it is not being driven by the tool. Note that the pull-up and pull-down resistors on the $\overline{\text{QACK}}$ signal are mutually exclusive and it is never necessary to populate both in a system. To preserve correct power-down operation, $\overline{\text{QACK}}$ should be merged via logic so that it also can be driven by the PCI bridge.

8.8 Thermal Management Information

This section provides thermal management information for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. To reduce the die-junction temperature, heat sinks may be attached to the package by several methods—adhesive, spring clip to holes in the printed-circuit board or package, and mounting clip and screw assembly; see Figure 25. This spring force should not exceed 5.5 pounds (2.5 kg) of force.

Figure 25 describes the package exploded cross-sectional view with several heat sink options.

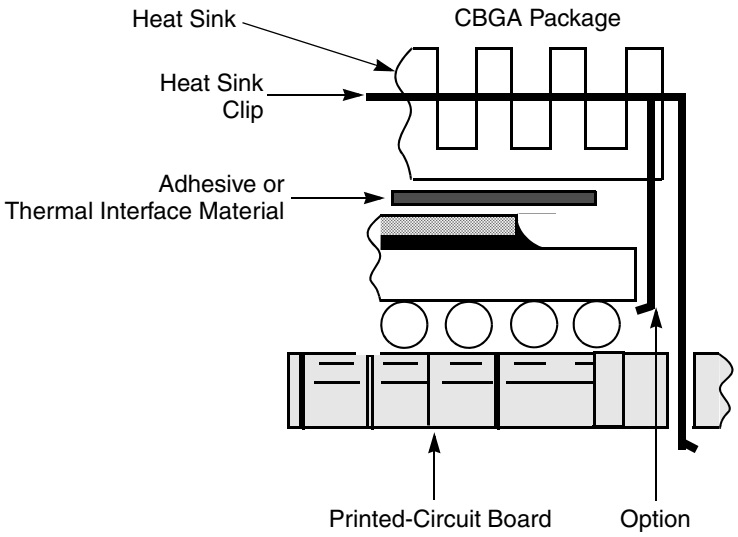


Figure 25. Package Exploded Cross-Sectional View with Several Heat Sink Options

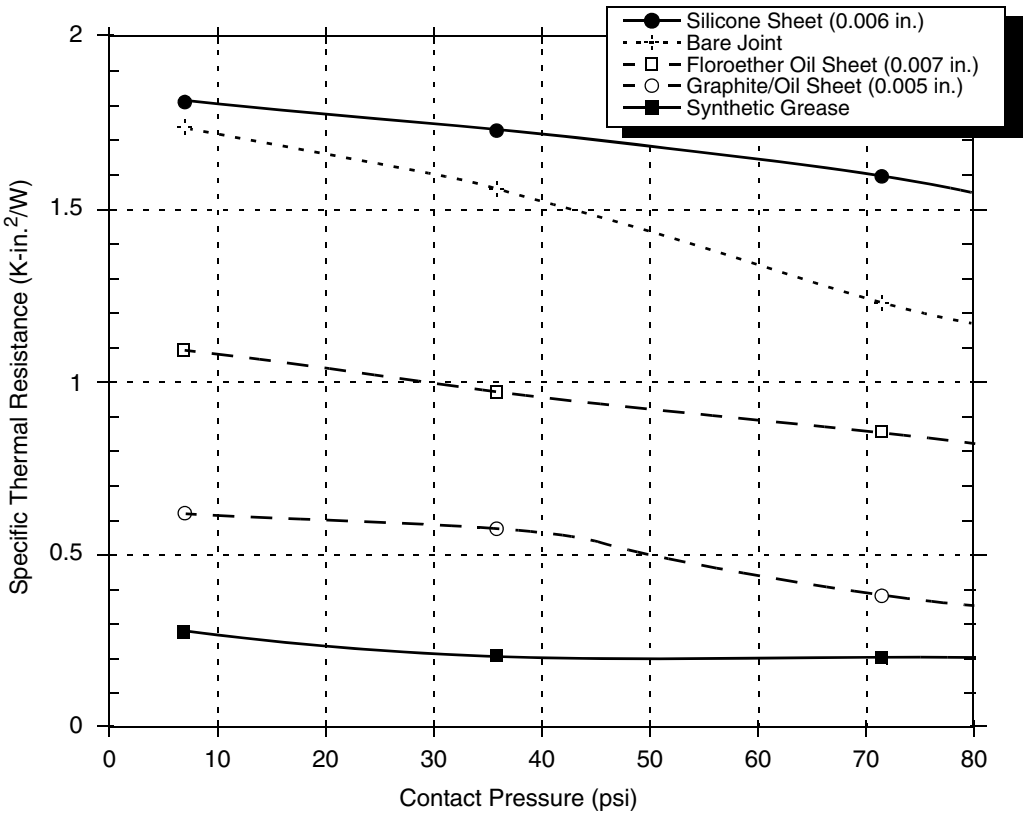


Figure 27. Thermal Performance of Select Thermal Interface Materials

The board designer can choose between several types of thermal interface. Heat sink adhesive materials should be selected based on high conductivity, yet adequate mechanical strength to meet equipment shock/vibration requirements. There are several commercially-available thermal interfaces and adhesive materials provided by the following vendors:

The Bergquist Company — 800-347-4572
18930 West 78th St.
Chanhassen, MN 55317
Internet: www.bergquistcompany.com

Chomerics, Inc. — 781-935-4850
77 Dragon Ct.
Woburn, MA 01888-4014
Internet: www.chomerics.com

Dow-Corning Corporation — 800-248-2481
Dow-Corning Electronic Materials
2200 W. Salzburg Rd.
Midland, MI 48686-0997
Internet: www.dow.com

Table 19. Document Revision History (continued)

Revision	Date	Substantive Change(s)
1	—	Corrected errors in Section 1.2.
		Removed references to MPC745 CBGA package in Sections 1.3 and 1.4.
		Added airflow values for θ_{JA} to Table 5.
		Corrected V_{IH} maximum for 1.8 V mode in Table 6.
		Power consumption values added to Table 7.
		Corrected t_{MXRH} in Table 9, deleted Note 2 application note reference.
		Added Max f_{L2CLK} and Min t_{L2CLK} values to Table 11.
		Updated timing values in Table 12.
		Corrected Note 2 of Table 13.
		Changed Table 14 to reflect I/F voltages supported.
		Removed 133 and 150 MHz columns from Table 16.
		Added document reference to Section 1.7.
		Added $\overline{\text{DBB}}$ to list of signals requiring pull-ups in Section 1.8.7.
		Removed log entries from Table 20 for revisions prior to public release.
0	—	Product announced. Documentation made publicly available.

10 Ordering Information

Ordering information for the devices fully covered by this specification document is provided in Section 10.1, “Part Numbers Fully Addressed by This Document.” Note that the individual part numbers correspond to a maximum processor core frequency. For available frequencies, contact your local Freescale sales office. In addition to the processor frequency, the part numbering scheme also includes an application modifier which may specify special application conditions. Each part number also contains a revision code which refers to the die mask revision number. Section 10.2, “Part Numbers Not Fully Addressed by This Document,” lists the part numbers which do not fully conform to the specifications of this document. These special part numbers require an additional document called a hardware specifications addendum.

10.1 Part Numbers Fully Addressed by This Document

Table 20 provides the Freescale part numbering nomenclature for the MPC755 and MPC745 devices fully addressed by this document.

Table 20. Part Numbering Nomenclature

MPC	*xxx*	*x*	*xx*	*nnn*	*x*	*x*
Product Code	**Part Identifier**	**Process Descriptor**	**Package [1]**	**Processor Frequency**	**Application Modifier**	**Revision Level**
XPC[2]	755 745	B = HiP4DP	PX = PBGA RX = CBGA	300 350	L: 2.0 V ± 100 mV 0° to 105°C	E: 2.8; PVR = 0008 3203
	755	C = HiP4DP		400		
MPC	755	B = HiP4DP		300 350		
		C = HiP4DP		350 400		
	745	B = HiP4DP	PX = PBGA	300 350		
	745	C = HiP4DP	PX = PBGA VT = PBGAPb-free BGA	350		
	755 745	B = HiP4DP	VT = PBGAPb-free BGA	300 350		
	755	C = HiP4DP		350 400		

Notes:

1. See Section 7, “Package Description,” for more information on available package types.
2. The X prefix in a Freescale part number designates a “Pilot Production Prototype” as defined by Freescale SOP 3-13. These are from a limited production volume of prototypes manufactured, tested, and Q.A. inspected on a qualified technology to simulate normal production. These parts have only preliminary reliability and characterization data. Before pilot production prototypes may be shipped, written authorization from the customer must be on file in the applicable sales office acknowledging the qualification status and the fact that product changes may still occur while shipping pilot production prototypes

10.2 Part Numbers Not Fully Addressed by This Document

Devices not fully addressed in this document are described in separate hardware specification addendums which supplement and supersede this document, as described in the following tables.

Table 21. Part Numbers Addressed by XPC755B*xxnnn*T*x* Series Part Numbers (Document No. MPC755ECSO1AD)

XPC	755	B	*xx*	*nnn*	T	*x*

Product Code	Part Identifier	Process Descriptor	Package	Processor Frequency	Application Modifier	Revision Level
XPC	755	B = HiP4DP	RX = CBGA	350 400	T: 2.0 V ± 100 mV –40° to 105°C	D: 2.7; PVR = 0008 3203 E: 2.8; PVR = 0008 3203
MPC	755	C=HiP4DP	RX = CBGA	350	T: 2.0 V ± 100 mV –40° to 105°C	E: 2.8; PVR = 0008 3203

Table 22. Part Numbers Addressed by XPC755B*xxnnn*LD Series Part Numbers (Document No. MPC755ECSO2AD)

XPC	*xxx*	B	*xx*	*nnn*	L	D

Product Code	Part Identifier	Process Descriptor	Package	Processor Frequency	Application Modifier	Revision Level
XPC	755 745	B = HiP4DP	PX = PBGA RX = CBGA	300 350 400	L: 2.0 V ± 100 mV 0° to 105°C	D: 2.7; PVR = 0008 3203

Table 23. Part Numbers Addressed by XPC755*xxxnnn*LE Series Part Numbers (Document No. MPC755ECSO3AD)

XPC	755	*x*	*xx*	*nnn*	L	E

Product Code	Part Identifier	Process Descriptor	Package	Processor Frequency	Application Modifier	Revision Level
XPC	755	B = HiP4DP	RX = CBGA	400	L: 2.0 V ± 100 mV 0° to 105°C	E: 2.8; PVR = 0008 3203
			PX = PBGA			
		C = HiP4DP	RX = CBGA	450		